The 2nd Tevatron Electron Lens and tests of a new electron gun in the framework of Beam-Beam Compensation project

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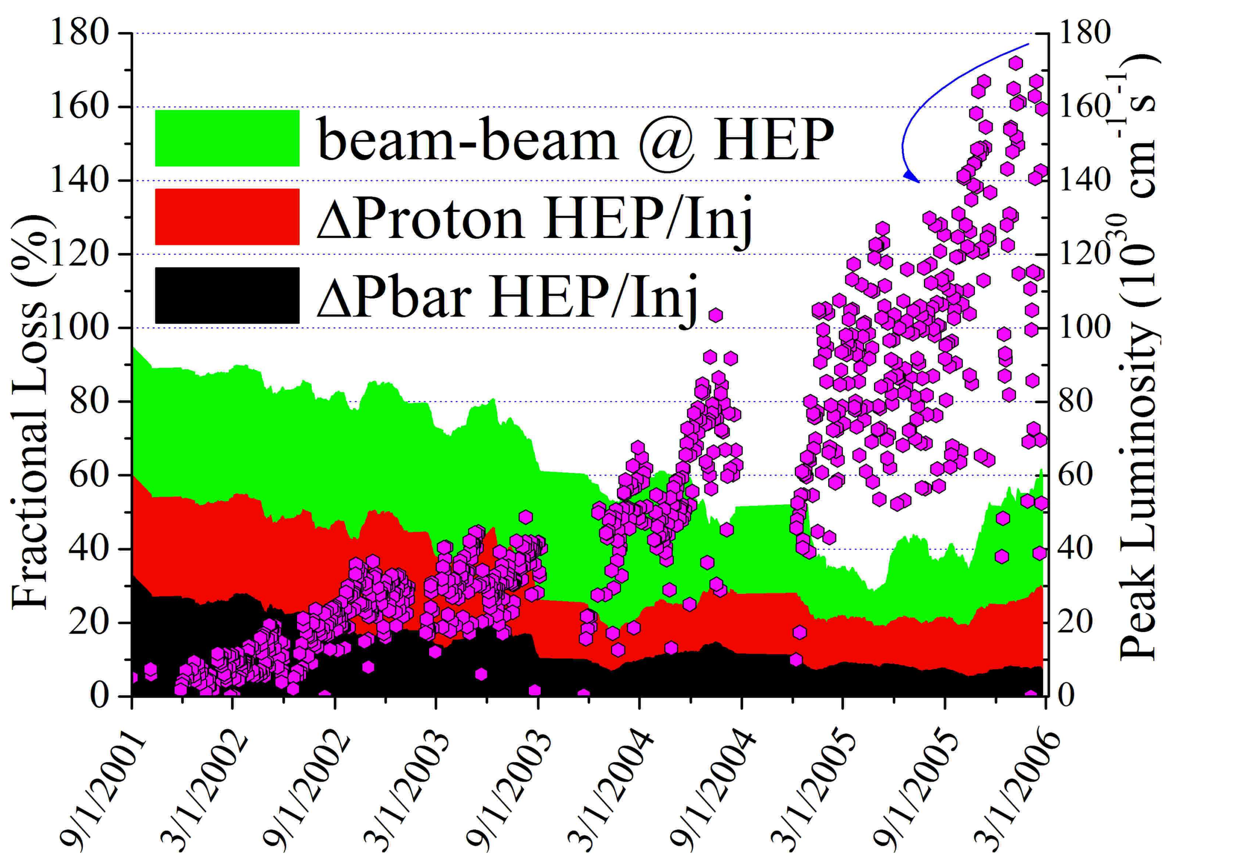
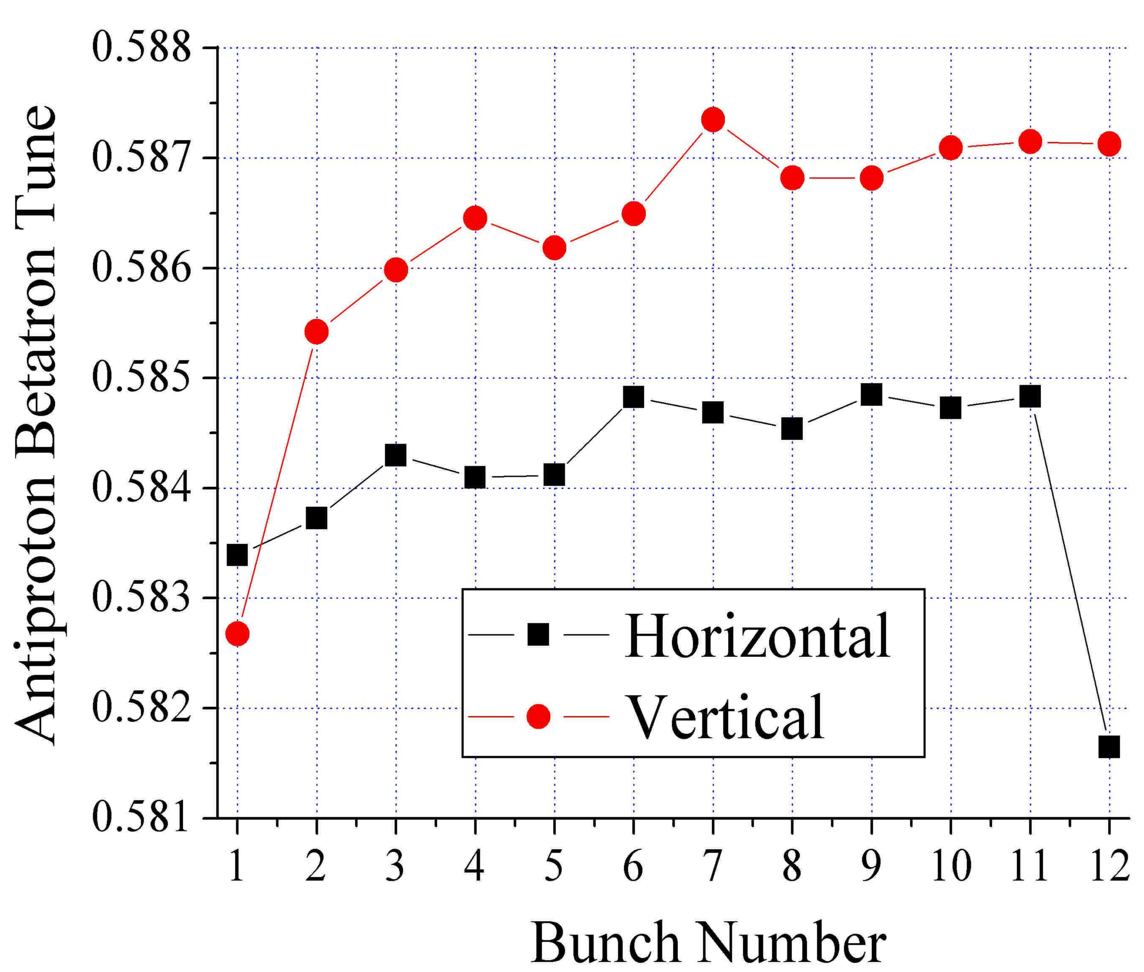
Introduction

Beam losses and peak luminosity in the Tevatron



Effects associated with both head on and parasitic beam-beam interaction have been observed in the Tevatron.

Bunch-by-bunch tune spread as a result of parasitic beam-beam interaction



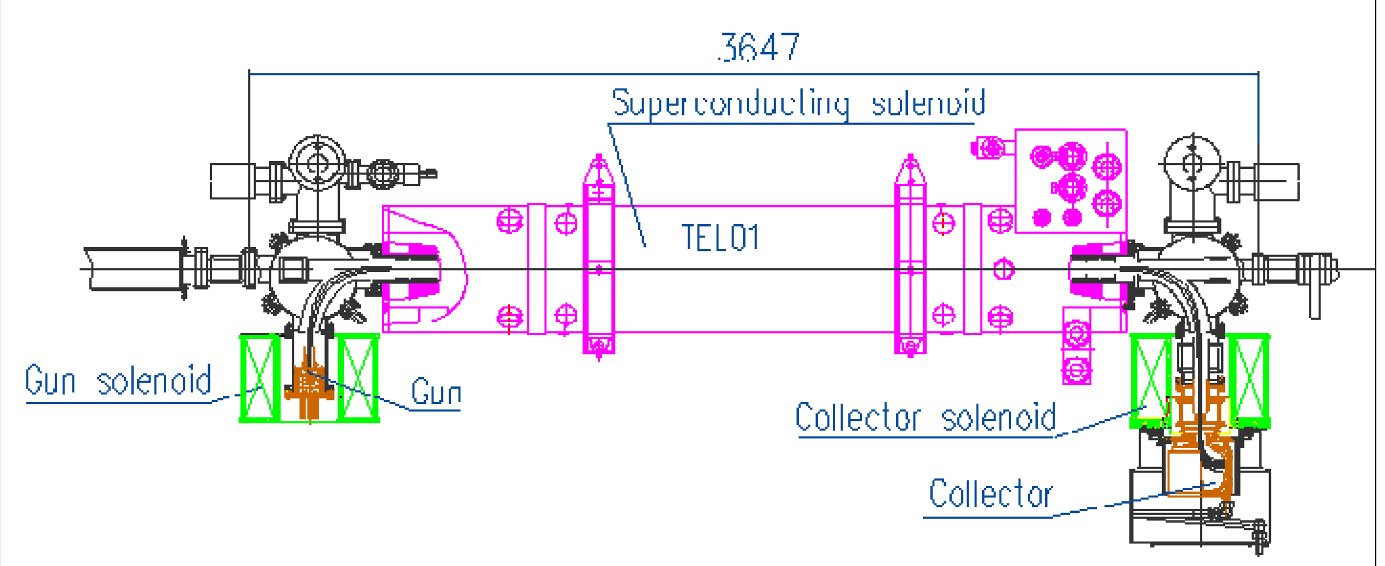
The goal of linear Beam-Beam Compensation (BBComp) is to reduce beam losses by reducing bunch-by-bunch tune spread. Bunches circulating in the machine have to be treated individually.

A device called Tevatron Electron Lens (TEL) has been designed and installed in 2001. Pulsed electron beam is placed on pbar/proton orbit. A number of beam studies showed tune shifts up to 0.009.

Project status, results

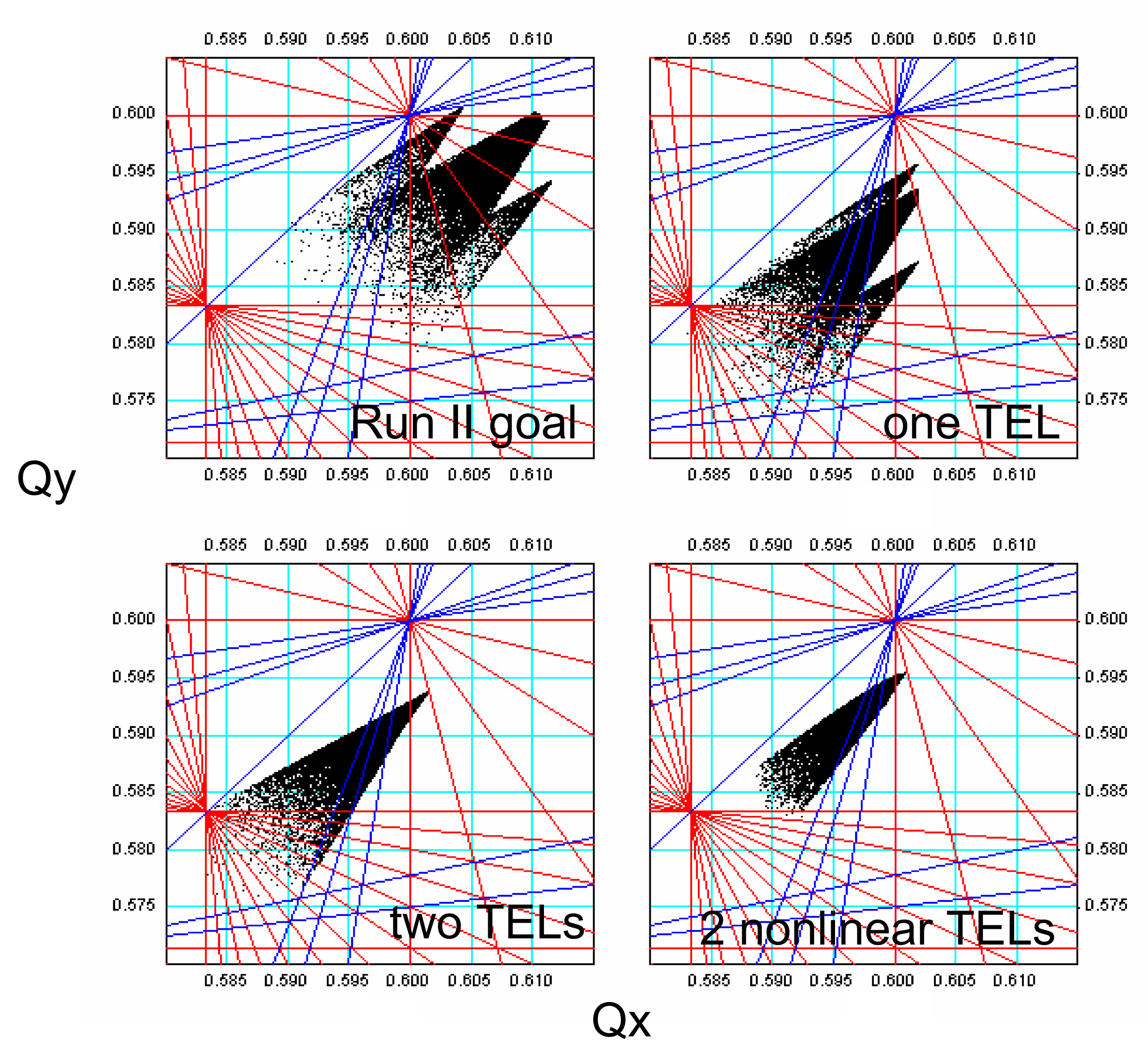
TEL1 has been used successfully to perform BBComp studies and became an operational device for abort gap cleaning.

TEL1 layout



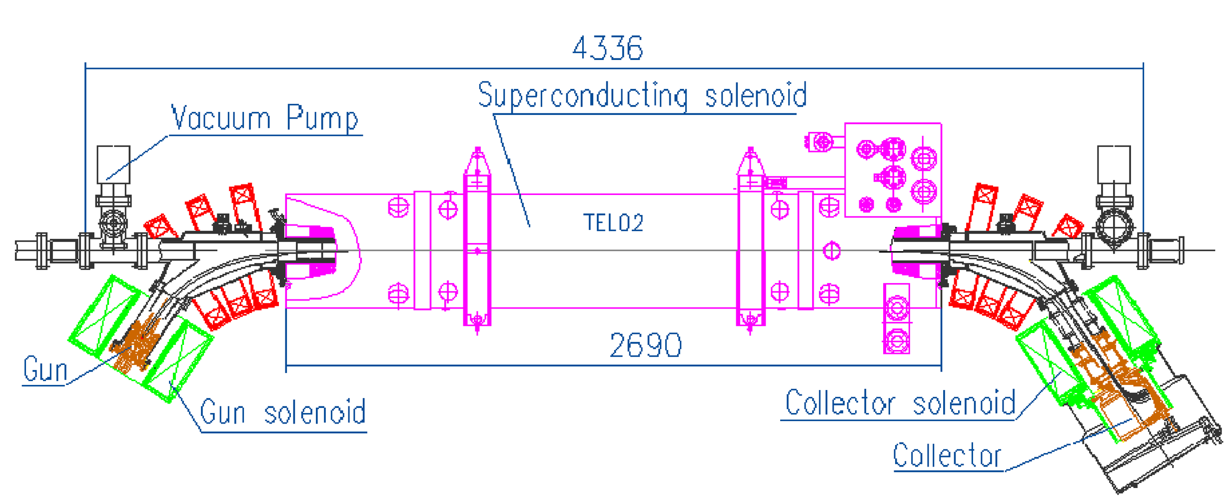
Calculations showed that a second TEL is needed in order to efficiently reduce tune spread in both planes

Calculated pbar tune spread

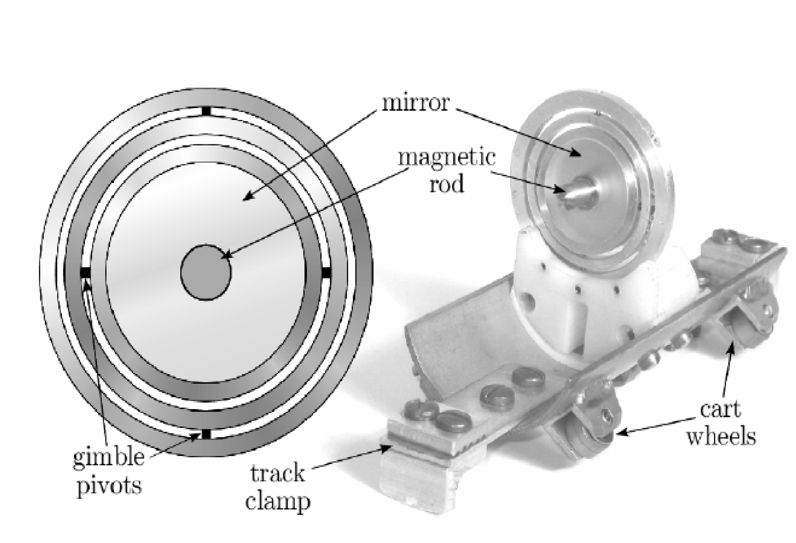


TEL1 and TEL2 layouts are different. TEL2 utilizes 57º bending angle instead of 90º in case of TEL1. Additional short solenoids has been added to increase magnetic field in both bends. This allows for much more flexibility in magnetic field settings.

TEL2 layout

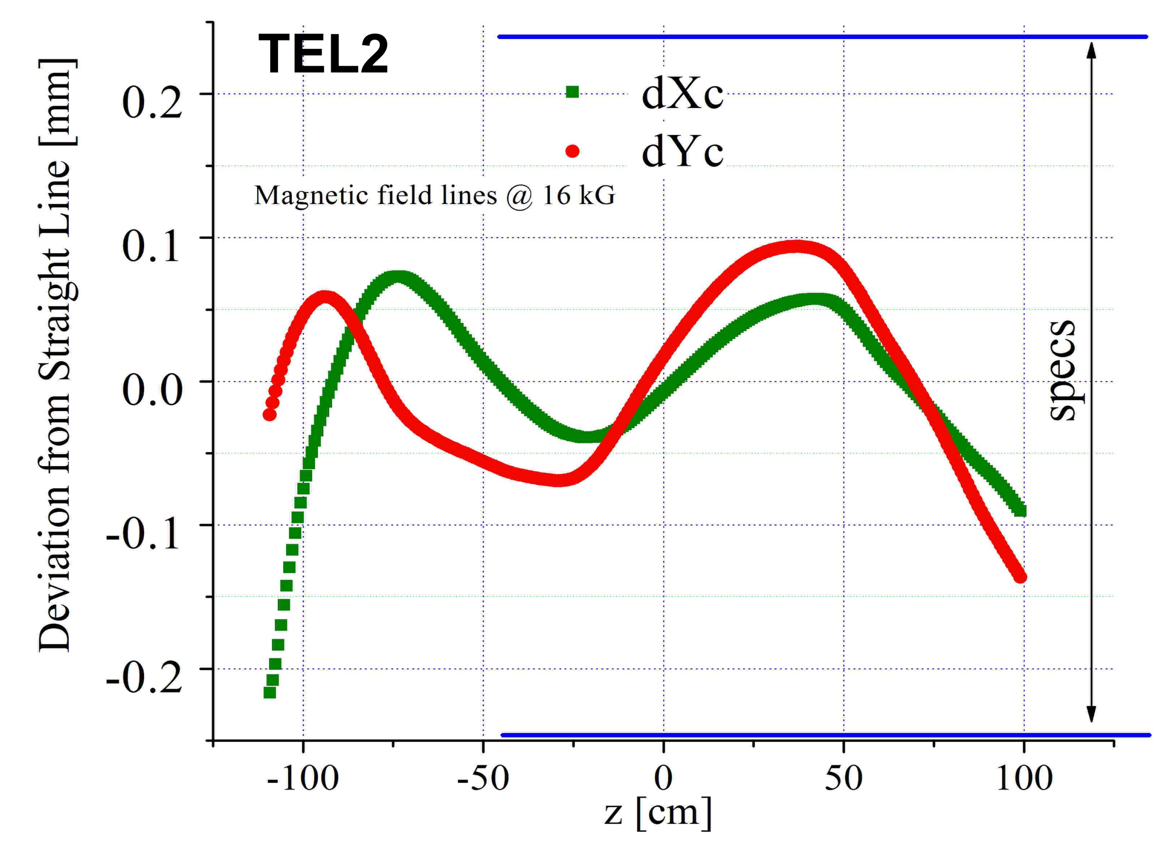


TEL2 has been tested prior to installation in the Tevatron. Magnetic field quality was measured using a hall probe and a laser based method. The second method utilizes a laser which is aligned along the solenoid axis. Its light is reflected by a magnetic mirror which is mounted on a cart dragged through the solenoid. The light is detected by means of a position sensitive detector. Since the mirror aligns itself perpendicular to magnetic field lines, the measured light spot position is a measure of magnetic line straightness. Measured straightness agrees with initial specification.

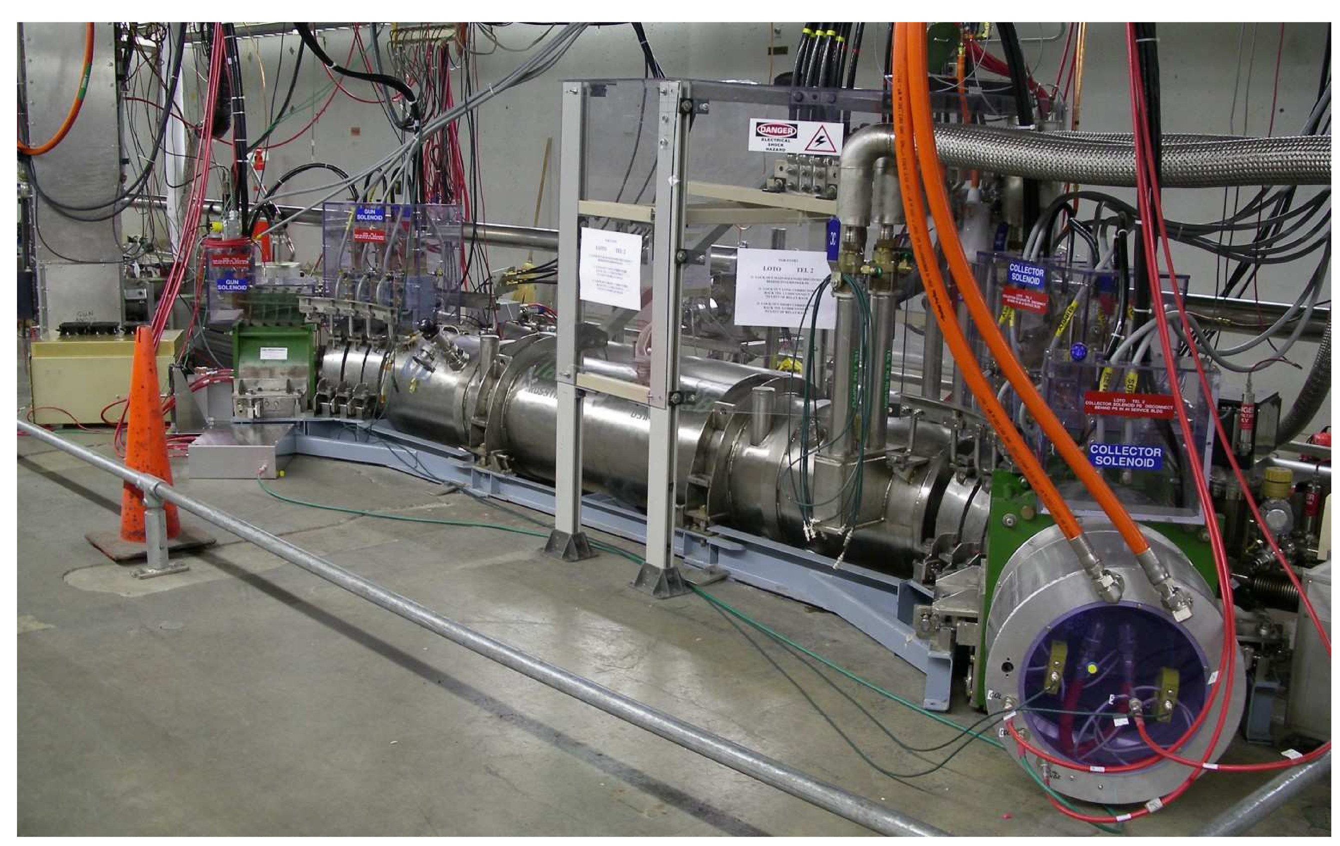


Mirror used to measure magnetic line straightness

Straightness of magnetic lines in the main solenoid



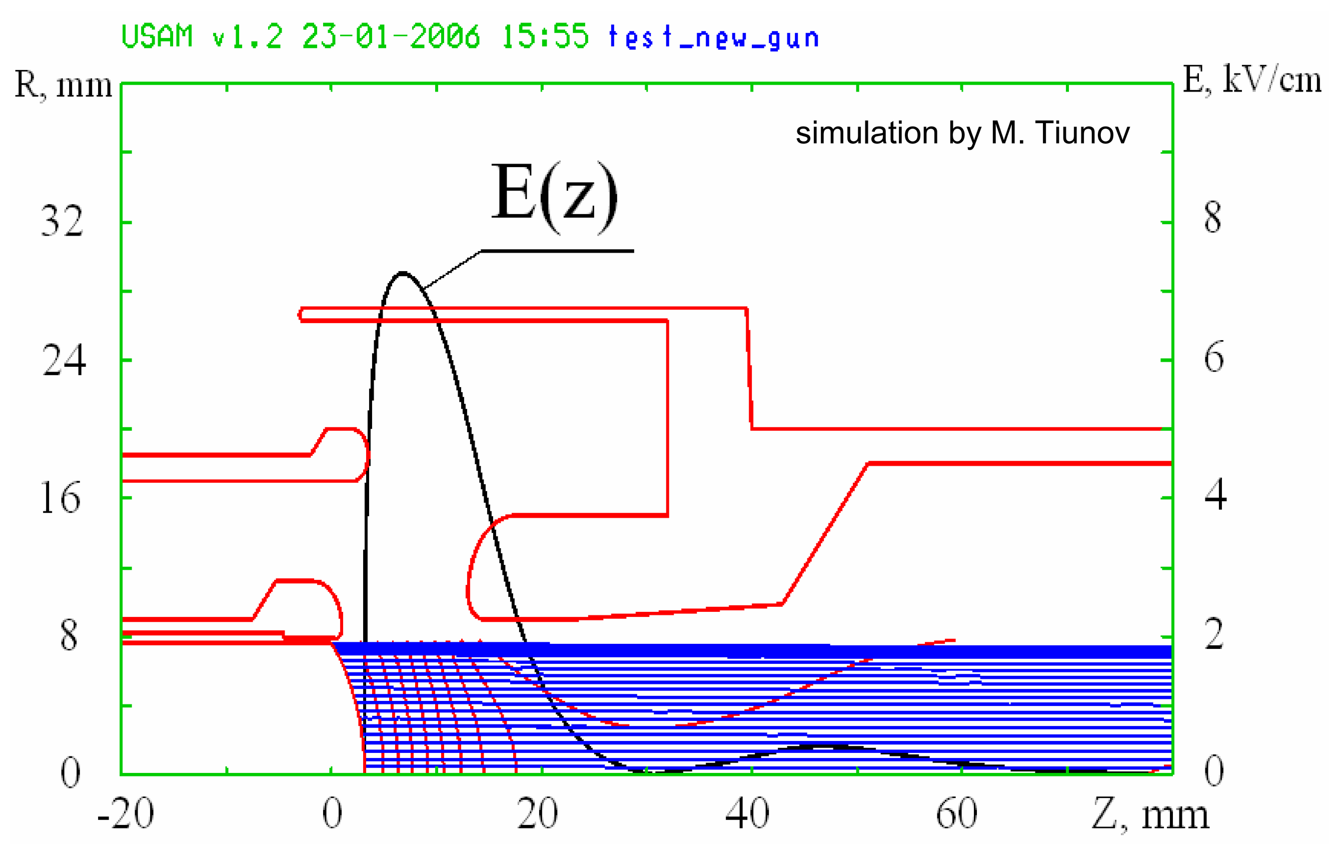
TEL2 installed in the Tevatron



Development of electron guns

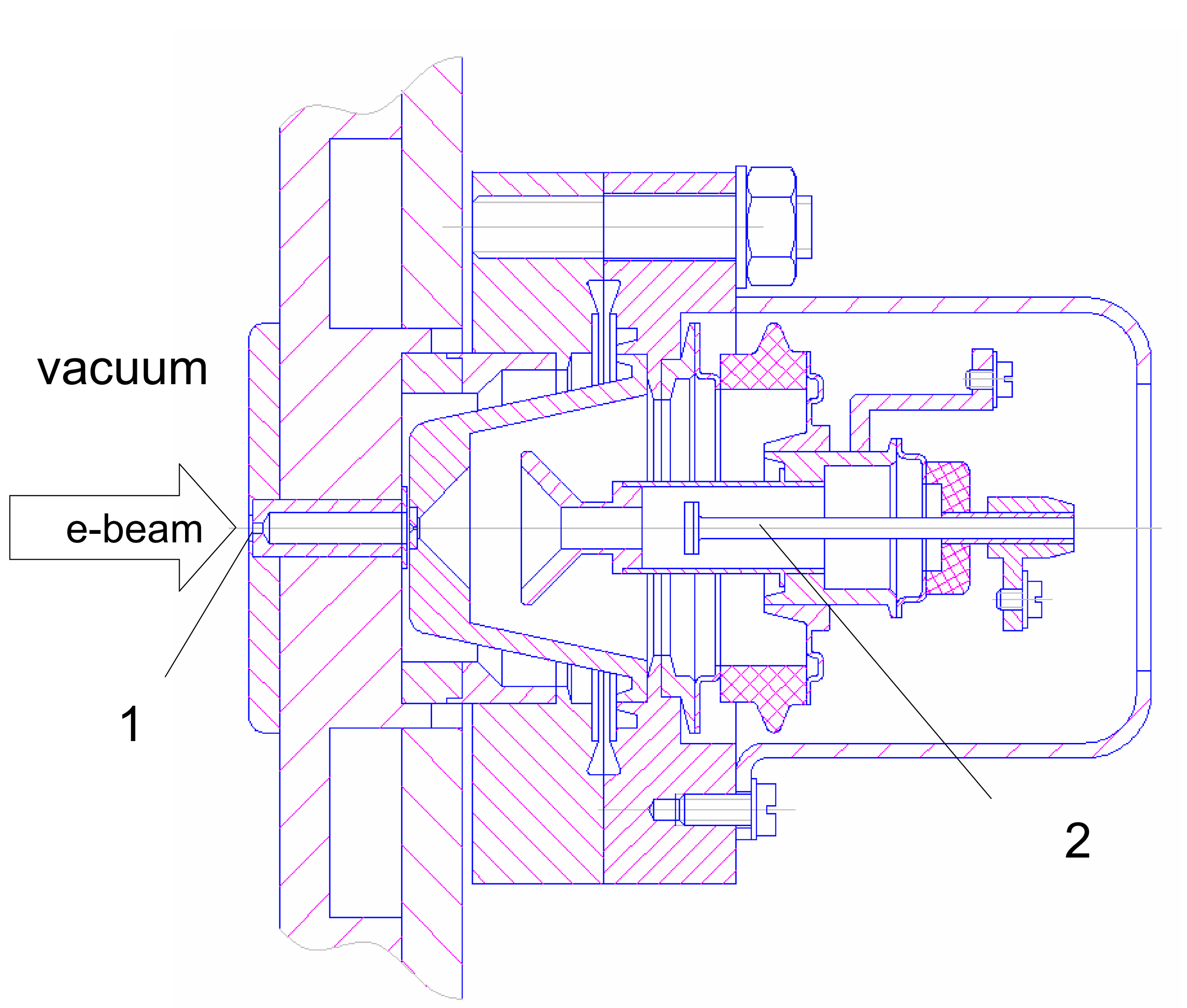
TEL1 was initially equipped with a high perveance gun that features uniform (flat) transverse charge distribution. Beam studies using this gun showed tune shifts up to 0.009 accompanied by high losses due to edge effects. A “gaussian” gun was introduced in 2002 and allowed to greatly reduce losses. To make e-beam alignment less critical and to increase the perveance a new smooth-edge-flat-top (SEFT) gun was commissioned in 2005 showing a good compromise between perveance and electron beam profile for linear BBComp.

Geometry and simulation of SEFT gun



Gun performance has been studied on the test bench. The collector of the test facility is equipped with a beam analyzer that allows to measure transverse distribution of e-current density (profile).

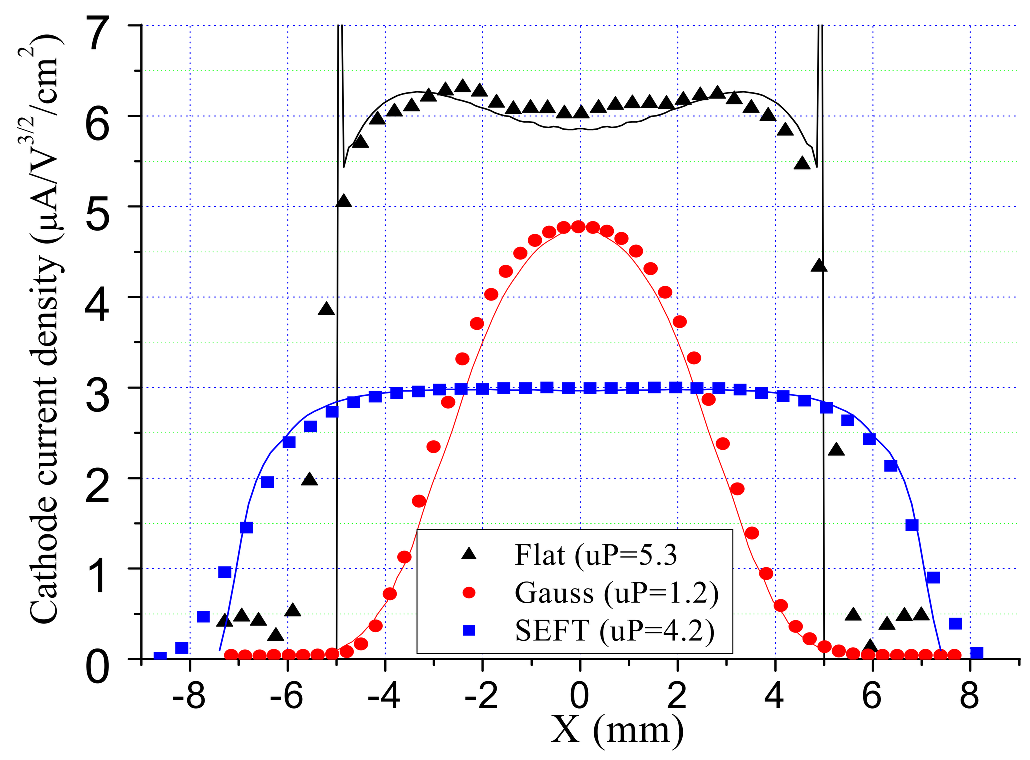
Beam analyzer



1 - 0.2 mm hole, 2 – current probe

A small fraction of a magnetized electron beam (propagating from left to right) passes through a 0.2 mm hole and hits the probe. Moving electron beam by means of horizontal and vertical corrector coils and simultaneously recording the probe current makes it possible to measure electron beam profiles.

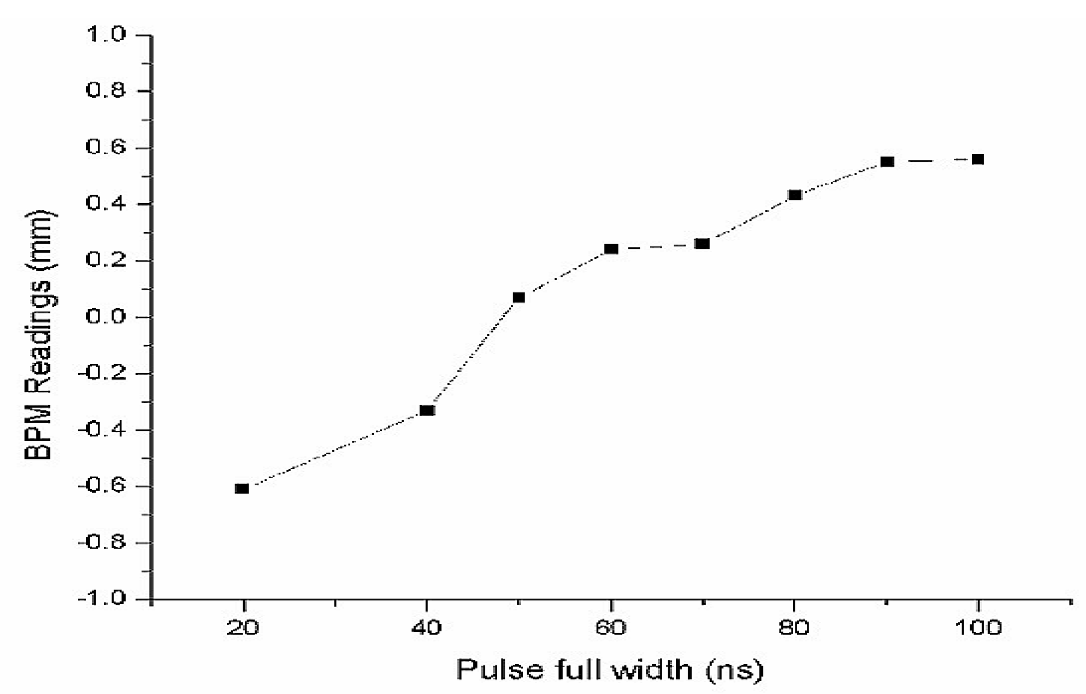
e-beam profiles, measured and calculated



Improvement of BPMs

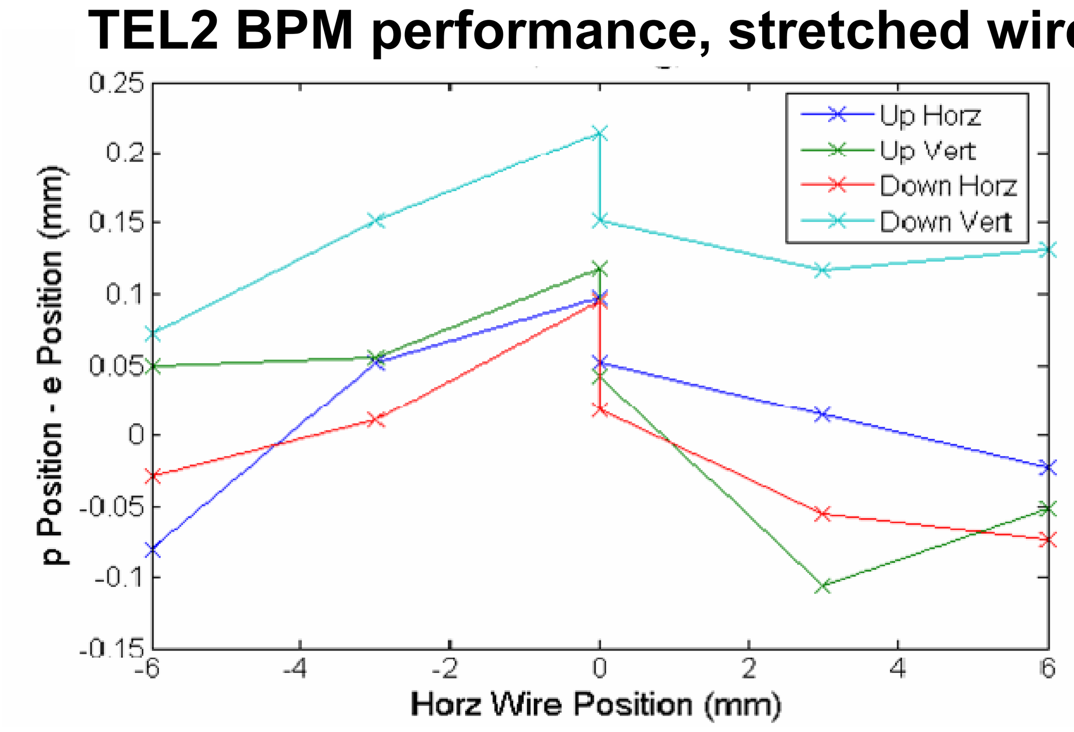
TEL1 BPMs (diagonally cut cylinders) are known to report different position depending on beam pulse width. The difference can be up to 1.2 mm.

TEL1: beam position vs pulse width



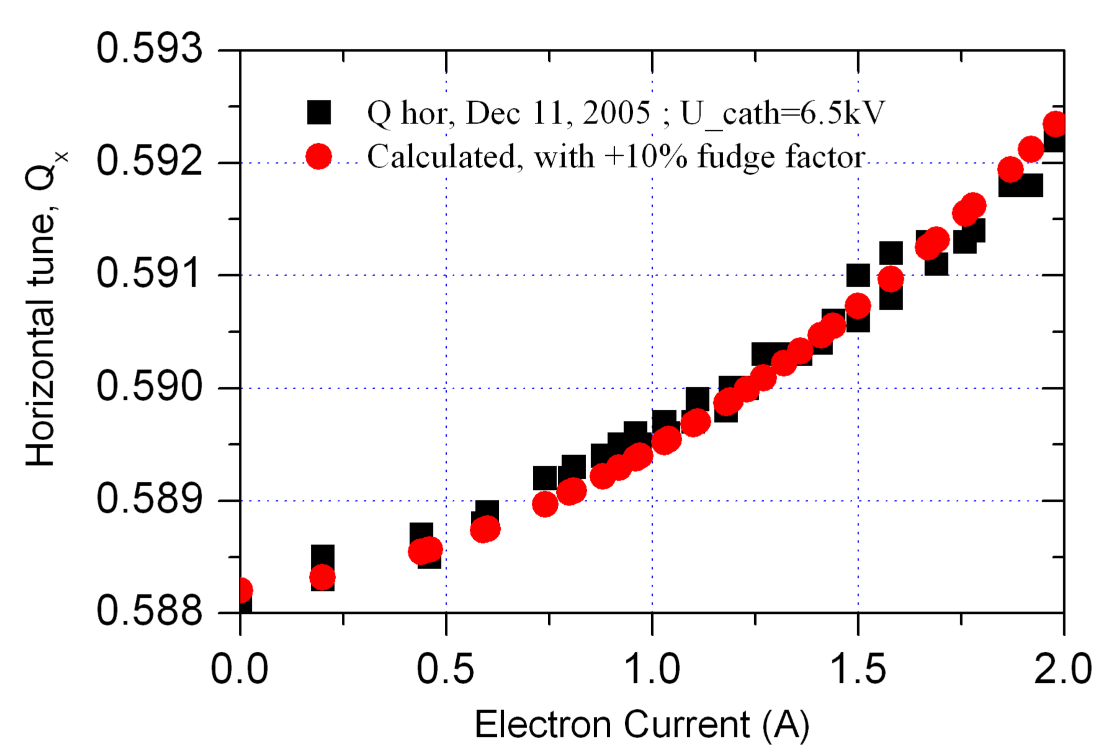
TEL2 BPM design utilizes four plate geometry with grounded electrodes between the plates to reduce crosstalk. They have been calibrated using a stretched wire and electron beam pulses of different width. The accuracy is better then 0.2 mm.

TEL2 BPM performance, stretched wire

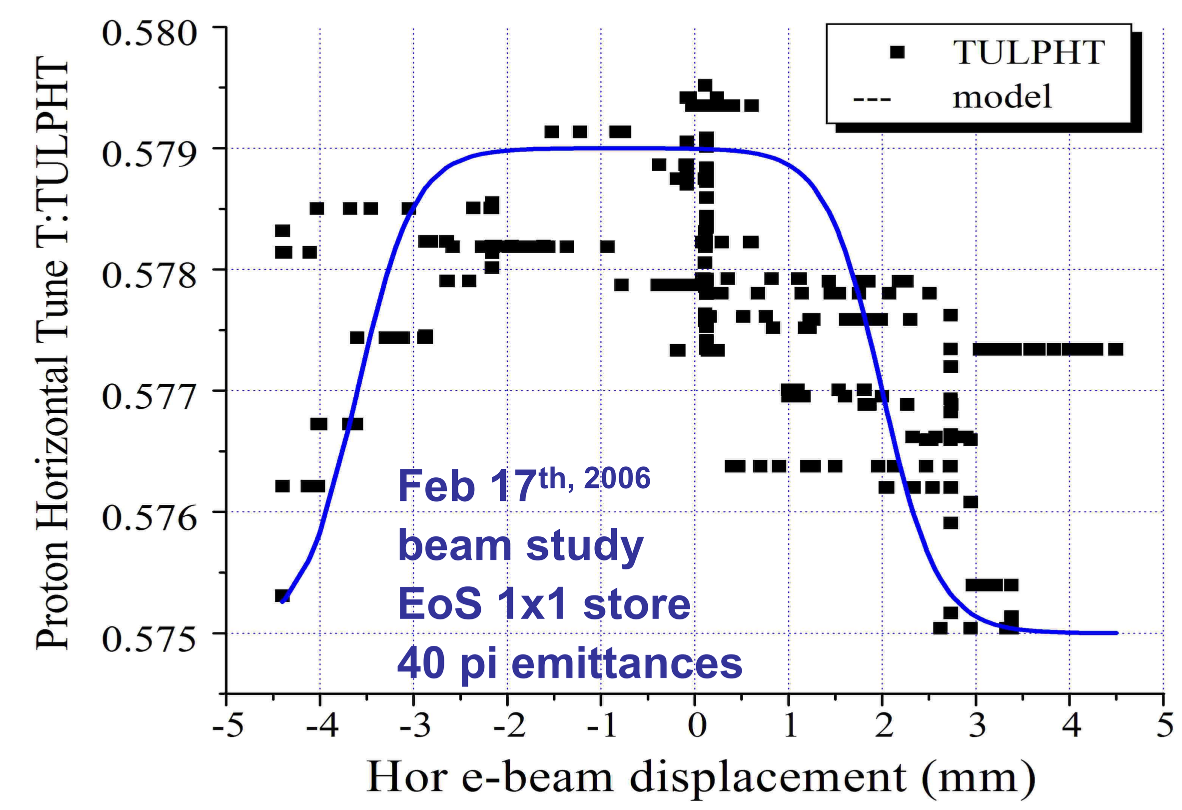


Measured tune shift and lifetime (TEL1)

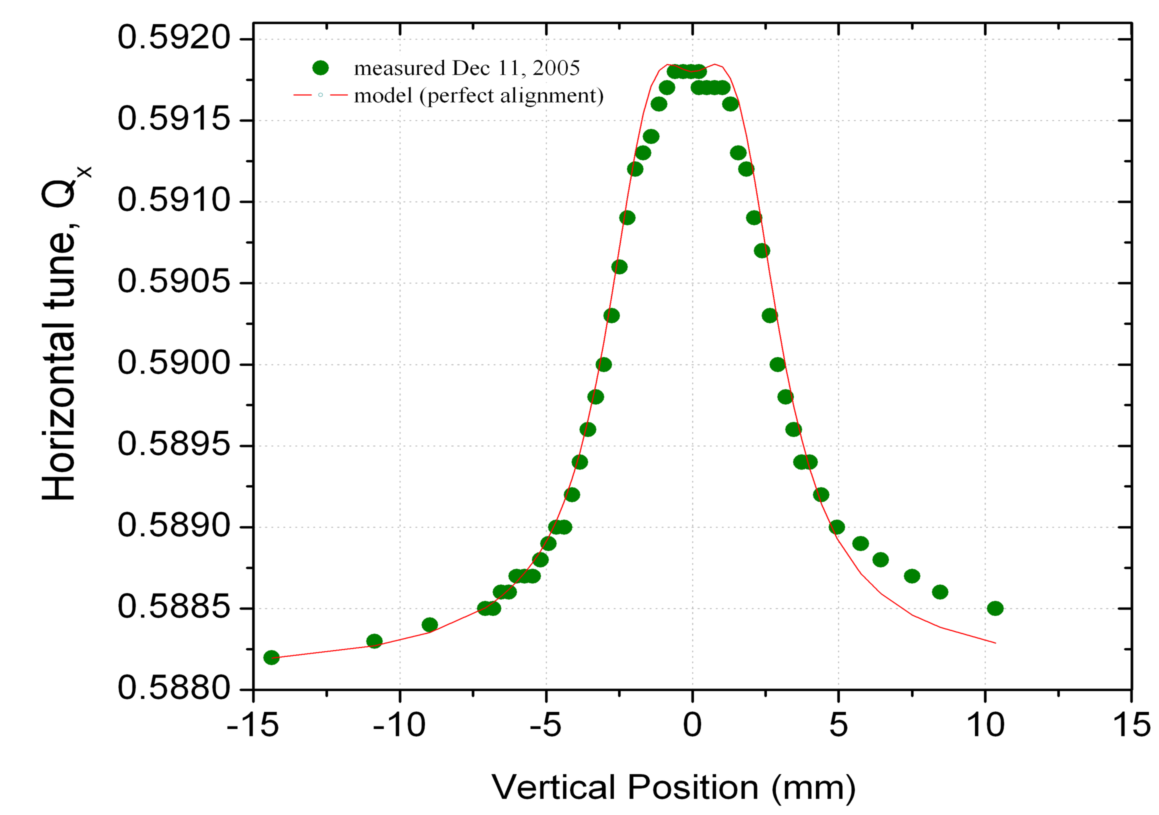
dQx vs e-current



dQx vs horizontal e-beam displacement



dQx vs vertical e-beam position



Using SEFT gun lifetimes of 700 hrs with dc e-beam and 340 hrs in pulsed regime have been observed. Presence of e-beam does not effect life time significantly. However, losses occur while tuning e-beam. Typically peak e-current was in the range 0.7-2 A.

Summary and plans

- TEL2 has been tested and installed in the Tevatron together with a new solid state high voltage modulator, commissioning underway
- TEL2 beam diagnostics has been improved
  - tests of new BPMs confirmed better accuracy
  - “scraping” electrode added
- A SEFT electron gun has been built studied on a test bench and commissioned. Beam studies confirmed the expected performance.

- Assemble two more SEFT guns (in manufacturing)
- Find an alternative way to clean the abort gap
- Use both TELs for Beam-Beam compensation
- Compensate many/all bunches simultaneously at low peak e-currents
- Improve e-beam stability/ripple to reduce losses
- Perform simulations of:
  - Lifetime vs e-beam alignment
  - How does the bend shape effect BBComp
  - Lifetime vs dispersion